



HYM5V72A804A N-Series

Buffered 8Mx72 bit EDO DRAM MODULE
based on 4Mx4 DRAM, with ECC, 3.3V, 4K-Refresh

GENERAL DESCRIPTION

The HYM5V72A804A N-Series is a 8Mx72-bit Extended Data Out mode CMOS DRAM module consisting of thirty-six HY51V16404A in 24/26 pin TSOP-II and two 16-bit BiCMOS line driver in TSSOP on a 168 pin glass-epoxy printed circuit board. 0.1 μ F and 0.01 μ F decoupling capacitors are mounted for each DRAM. The HYM5V72A804ATNG is Gold plated socket type Dual In-line Memory Module suitable for easy interchange and addition of 64M byte memory.

FEATURES

- 168-Pin Buffered DIMM
- Extended Data Out Operation
- /CAS-before-/RAS, /RAS-only, Hidden and Self refresh capability
- 4096 refresh cycles / 256ms (SL-part)
4096 refresh cycles / 64ms
- Fast access time and cycle time

Speed	tRAC	tCAC	tHPC
60	60ns	15ns	25ns
70	70ns	18ns	30ns
80	80ns	20ns	35ns

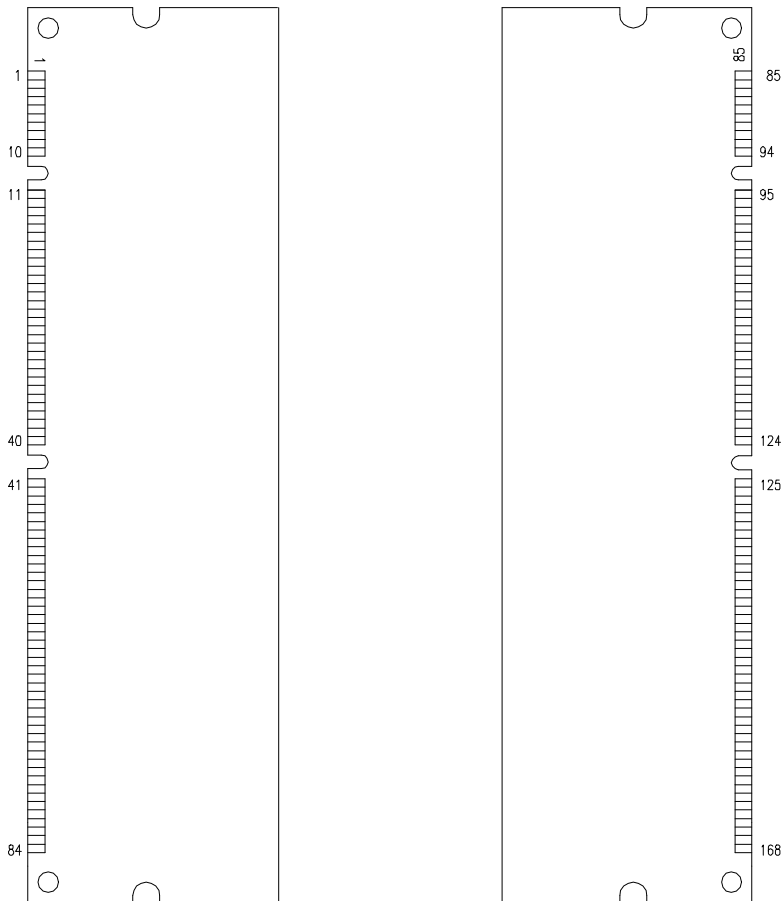
- Single power supply of 3.3V $\pm$ 0.3V
- Low power dissipation
 - Max. self-refresh : 39.5mW (SL-part)
 - Max. battery back-up : 78.4mW (SL-part)
 - Max. CMOS standby : 26.6mW (SL-part)
65.5mW
 - Max. TTL standby : 130mW
 - Max. operating

Speed	Power
60	5.93W
70	5.28W
80	4.64W

- LVTTTL compatible inputs and outputs
- JEDEC standard pinout
- Buffered inputs (except /RAS and DQ)
- 4 Byte interleave enabled,
Dual address inputs (A0,B0)

ORDERING INFORMATION

PART NUMBER	SPEED	FEATURES	PACKAGE	PLATING
HYM5V72A804ATNG	60/70/80	EDO, 4K, 3.3V, TSOP	DIMM	Gold

PIN CONNECTION

PIN DISCRIPTION

/RAS0~/RAS3	Row Address Strobe
/CAS0, /CAS4, /CAS1, /CAS5	Column Address Strobe
/WE0, /WE2	Write Enable
/OE0, /OE2	Output Enable
A0~A11, B0	Address Input
DQ0~DQ71	Data Input / Output
PD1~PD8	Presence Detect
/PDE	Presence Detect Enable
ID0, ID1	ID Bit
VCC	Power (+3.3V)
VSS	Ground

PIN ASSIGNMENTS

#	NAME	#	NAME	#	NAME	#	NAME
1	VSS	43	VSS	85	VSS	127	VSS
2	DQ0	44	/OE2	86	DQ36	128	NC
3	DQ1	45	/RAS2	87	DQ37	129	/RAS3
4	DQ2	46	/CAS4	88	DQ38	130	/CAS5
5	DQ3	47	NC	89	DQ39	131	NC
6	VCC	48	/WE2	90	VCC	132	PDE
7	DQ4	49	VCC	91	DQ40	133	VCC
8	DQ5	50	NC	92	DQ41	134	NC
9	DQ6	51	NC	93	DQ42	135	NC
10	DQ7	52	DQ18	94	DQ43	136	DQ54
11	DQ8	53	DQ19	95	DQ44	137	DQ55
12	VSS	54	VSS	96	VSS	138	VSS
13	DQ9	55	DQ20	97	DQ45	139	DQ56
14	DQ10	56	DQ21	98	DQ46	140	DQ57
15	DQ11	57	DQ22	99	DQ47	141	DQ58
16	DQ12	58	DQ23	100	DQ48	142	DQ59
17	DQ13	59	VCC	101	DQ49	143	VCC
18	VCC	60	DQ24	102	VCC	144	DQ60
19	DQ14	61	NC	103	DQ50	145	NC
20	DQ15	62	NC	104	DQ51	146	NC
21	DQ16	63	NC	105	DQ52	147	NC
22	DQ17	64	NC	106	DQ53	148	NC
23	VSS	65	DQ25	107	VSS	149	DQ61
24	NC	66	DQ26	108	NC	150	DQ62
25	NC	67	DQ27	109	NC	151	DQ63
26	VCC	68	VSS	110	VCC	152	VSS
27	/WE0	69	DQ28	111	NC	153	DQ64
28	/CAS0	70	DQ29	112	/CAS1	154	DQ65
29	NC	71	DQ30	113	NC	155	DQ66
30	/RAS0	72	DQ31	114	/RAS1	156	DQ67
31	/OE0	73	VCC	115	NC	157	VCC
32	VSS	74	DQ32	116	VSS	158	DQ68
33	A0	75	DQ33	117	A1	159	DQ69
34	A2	76	DQ34	118	A3	160	DQ70
35	A4	77	DQ35	119	A5	161	DQ71
36	A6	78	VSS	120	A7	162	VSS
37	A8	79	PD1	121	A9	163	PD2
38	A10	80	PD3	122	A11	164	PD4
39	NC	81	PD5	123	NC	165	PD6
40	VCC	82	PD7	124	VCC	166	PD8
41	NC	83	ID0	125	NC	167	ID1
42	NC	84	VCC	126	B0	168	VCC

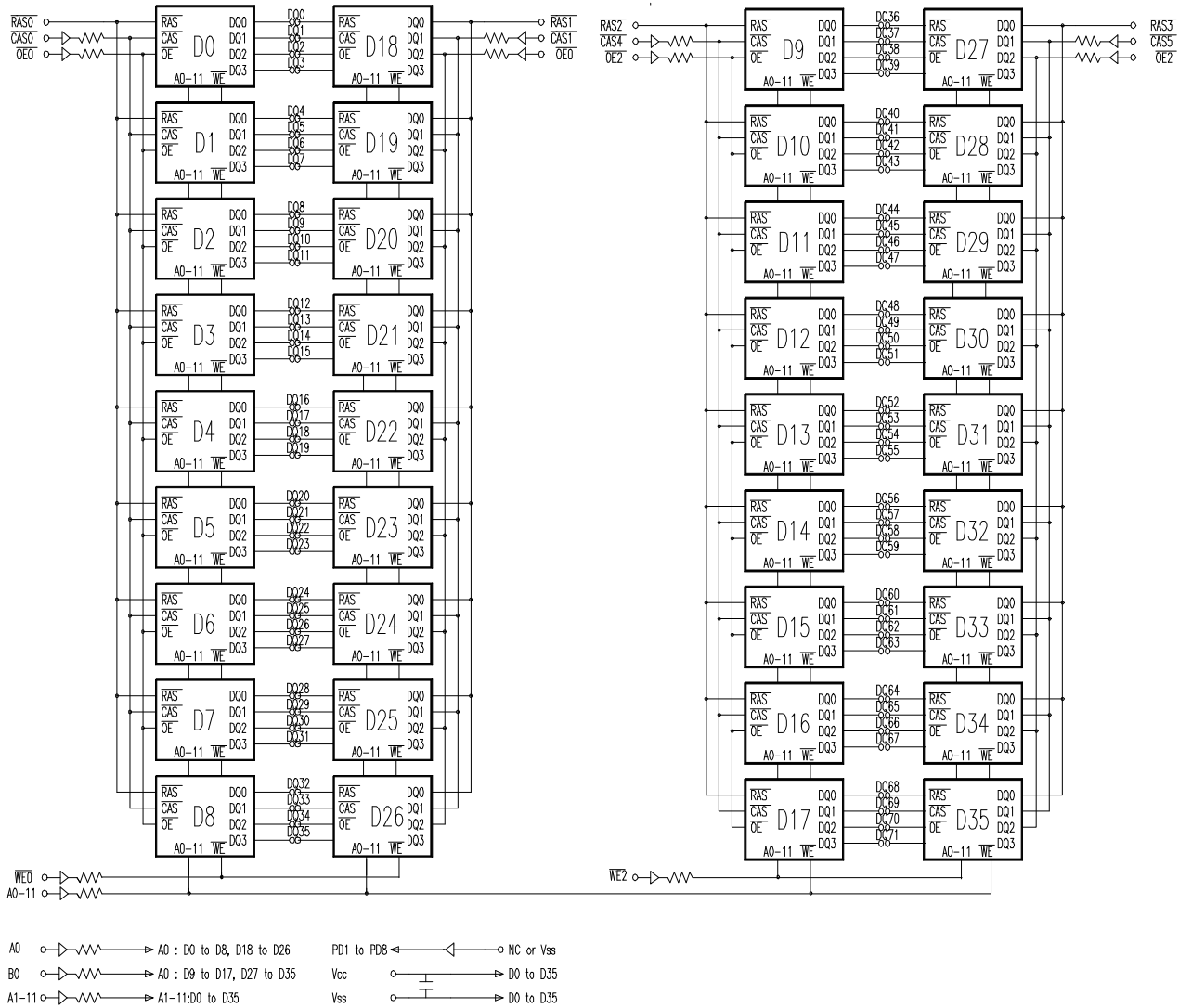
PRESENCE DETECT PINS

Speed	PD1	PD2	PD3	PD4	PD5	PD6	PD7	PD8	ID0	ID1
60	VSS	VSS	NC	NC	NC	NC	NC	VSS	VSS	NC or VSS
70	VSS	VSS	NC	NC	NC	VSS	NC	VSS	VSS	NC or VSS
80	VSS	VSS	NC	NC	NC	NC	VSS	VSS	VSS	NC or VSS

NOTE :

1. PDs are either open NC or Driven to VSS via on-board buffer circuits.
2. IDs are connected directly to NC or VSS without a buffer.
3. ID1 will be either open NC for Self-Refresh or driven to VSS for standard.

BLOCK DIAGRAM



NOTE : All resistors are 25 Ohm $\pm$ 5%

ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	RATING	UNIT
TA	Ambient Temperature	0 to 70	°C
TSTG	Storage Temperature	-55 to 150	°C
VIN, VOUT	Voltage on Any Pin relative to VSS	-0.5 to 4.6	V
VCC	Voltage on VCC relative to VSS	-0.5 to 4.6	V
IOS	Short Circuit Output Current	50	mA
PD	Power Dissipation	38.4	W

NOTE : Operation at or above Absolute Maximum Ratings can adversely affect device reliability.

RECOMMENDED DC OPERATING CONDITIONS

(TA=0°C to 70°C)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
VCC	Power Supply Voltage	3.0	3.3	3.6	V
VIH	Input High Voltage	2.0	-	VCC+0.3	V
VIL	Input Low Voltage	-0.3	-	0.8	V

NOTE : All voltages are referenced to VSS.

DC CHARACTERISTICS

($T_A=0^{\circ}\text{C}$ to 70°C , $V_{CC}=3.3\text{V} \pm 0.3\text{V}$ and $V_{SS}=0\text{V}$, unless otherwise noted.)

Symbol	Parameter	Test Condition	Speed/ Power	Max. Current	UNIT
				4K Ref	
ICC1	Operating Current	/RAS and /CAS cycling $t_{RC}=t_{RC}$ (min.)	60 70 80	1650 1470 1290	mA
ICC2	LVTTL Standby Current	/RAS = /CAS $\geq V_{IH}$ other inputs $\geq V_{SS}$		36.2	mA
ICC3	/RAS-only Refresh Current	/CAS = V_{IH} , /RAS cycling $t_{RC} = t_{RC}$ (min.)	60 70 80	1650 1470 1290	mA
ICC4	EDO Mode Current	/RAS = V_{IL} , /CAS, Address cycling $t_{HPC} = t_{HPC}$ (min.)	60 70 80	1470 1290 1110	mA
ICC5	CMOS Standby Current	/RAS = /CAS $\geq V_{CC}-0.2\text{V}$	SL-part	18.2 7.4	mA mA
ICC6	/CAS-before- /RAS Refresh Current	/RAS and /CAS cycling $t_{RC}=t_{RC}$ (min.)	60 70 80	1650 1470 1290	mA
ICC7	Battery Back-up Current (SL-part)	$t_{RC} = 62.5\mu\text{s}$ /CAS = CBR cycling or 0.2V /OE & /WE = $V_{CC} - 0.2\text{V}$ Address = $V_{CC}-0.2\text{V}$ or 0.2V DQ = $V_{CC}-0.2\text{V}$, 0.2V or open	$t_{RAS} \leq 300\text{ns}$	12.8	mA
			$t_{RAS} \leq 1\mu\text{s}$	21.8	mA
ICC8	Self Refresh Current (SL-part)	/RAS & /CAS = 0.2V Other pins are same as ICC7		11	mA

Symbol	Parameter	Test condition		Min.	Max.	UNIT
ILI	Input Leakage current (Any Input)	$V_{SS} \leq V_{IN} \leq V_{CC} + 0.3$ All other pins not under test = V_{SS}	All but /RAS /RAS	-10 -90	10 90	μA
ILO	Output Leakage current (Any Input)	$V_{SS} \leq V_{OUT} \leq V_{CC}$ /RAS & /CAS at V_{IH}		-20	20	μA
VOL	Output Low Voltage	$I_{OL} = 2.0\text{mA}$		-	0.4	V
VOH	Output High Voltage	$I_{OH} = -2.0\text{mA}$		2.4	-	V

NOTE

1. ICC1, ICC3, ICC4 and ICC6 depend on output loading and cycle rates(t_{RC} and t_{HPC}).
2. Specified values are obtained with outputs unloaded.
3. ICC is specified as an average current. In ICC1, ICC3, ICC6, address can be changed only once while /RAS= V_{IL} . In ICC4, address can be changed maximum once while /CAS= V_{IH} within one EDO mode cycle time t_{HPC} .
4. Only /RAS(max.) = $1\mu\text{s}$ is applied to refresh of battery backup but $t_{RAS}(\text{max.}) = 10\mu\text{s}$ is applied to normal functional operation.
5. ICC5(max.) = 7.4mA, ICC7 and ICC8 are applied to SL-part only.

AC CHARACTERISTICS

(T_A=0°C to 70°C, VCC=3.3V ± 0.3V and VSS=0V, unless otherwise noted.)

#	SYMBOL	PARAMETER	HYM5V72A804A N-Series						UNIT	NOTE
			-60		-70		-80			
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
1	tRC	Random Read or Write Cycle Time	110	-	130	-	150	-	ns	
2	tRWC	Read-Modify-Write Cycle Time	163	-	188	-	208	-	ns	13
3	tHPC	EDO Mode Cycle Time	25	-	30	-	35	-	ns	2
4	tHPRWC	EDO Mode Read-Modify-Write Cycle Time	78	-	88	-	98	-	ns	2,13
5	tRAC	Access Time from /RAS	-	60	-	70	-	80	ns	5,6,7
6	tCAC	Access Time from /CAS	-	20	-	23	-	25	ns	5,6,13
7	tAA	Access Time from Column Address	-	35	-	40	-	45	ns	5,7,13
8	tCPA	Access Time from Column Precharge	-	40	-	45	-	50	ns	5,13
9	tCLZ	/CAS to Output Low Impedance	8	-	8	-	8	-	ns	5,13
10	tCEZ	Out Buffer Turn-Off Delay Time from /CAS	8	20	8	23	8	25	ns	8,13
11	tT	Transition Time (Rise and Fall)	2	50	2	50	2	50	ns	3
12	tRP	/RAS Precharge Time	40	-	50	-	60	-	ns	
13	tRAS	/RAS Pulse Width	60	10K	70	10K	80	10K	ns	
14	tRASP	/RAS Pulse Width (EDO Mode)	60	200K	70	200K	80	200K	ns	
15	tRSH	/RAS Hold Time	20	-	23	-	25	-	ns	13
16	tCSH	/CAS Hold Time	43	-	48	-	53	-	ns	13
17	tCAS	/CAS Pulse Width	11	10K	14	10K	17	10K	ns	
18	tRCD	/RAS to /CAS Delay Time	18	40	18	47	18	55	ns	6,13
19	tRAD	/RAS to Column Address Delay Time	13	25	13	30	15	35	ns	7,13
20	tCRP	/CAS to /RAS Precharge Time	10	-	10	-	10	-	ns	11,13
21	tCP	/CAS Precharge Time	10	-	12	-	14	-	ns	
22	tASR	Row Address Set-up Time	5	-	5	-	5	-	ns	13
23	tRAH	Row Address Hold Time	8	-	8	-	10	-	ns	13
24	tASC	Column Address Set-up Time	0	-	0	-	0	-	ns	
25	tCAH	Column Address Hold Time	10	-	10	-	15	-	ns	
26	tRAL	Column Address to /RAS Lead Time	35	-	40	-	45	-	ns	13
27	tRCS	Read Command Set-up Time	0	-	0	-	0	-	ns	
28	tRCH	Read Command Hold Time Referenced to /CAS	0	-	0	-	0	-	ns	9
29	tRRH	Read Command Hold Time Referenced to /RAS	-2	-	-2	-	-2	-	ns	9,13
30	tWCH	Write Command Hold Time	10	-	10	-	15	-	ns	
31	tWP	Write Command Pulse Width	10	-	10	-	15	-	ns	
32	tRWL	Write Command to /RAS Lead Time	17	-	17	-	22	-	ns	13
33	tCWL	Write Command to /CAS Lead Time	12	-	12	-	17	-	ns	

AC CHARACTERISTICS

(Continued)

#	SYMBOL	PARAMETER	HYM5V72A804A N-Series						UNIT	NOTE
			-60		-70		-80			
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
34	tDS	Data-In Set-up Time	-2	-	-2	-	-2	-	ns	10,13
35	tDH	Data-In Hold Time	15	-	15	-	15	-	ns	10,13
36	tREF	Refresh Period (4096 cycles)	-	64	-	64	-	64	ms	
		Refresh Period (SL-part)	-	256	-	256	-	256	ms	
37	tWCS	Write Command Set-up Time	0	-	0	-	0	-	ns	11
38	tCWD	/CAS to /WE Delay Time	34	-	40	-	44	-	ns	11
39	tRWD	/RAS to /WE Delay Time	77	-	90	-	102	-	ns	11,13
40	tAWD	Column Address to /WE Delay Time	49	-	57	-	64	-	ns	11
41	tCSR	/CAS Set-up Time (CBR Cycle)	10	-	10	-	10	-	ns	13
42	tCHR	/CAS Hold Time (CBR Cycle)	8	-	8	-	8	-	ns	13
43	tRPC	/RAS to /CAS Precharge Time	3	-	3	-	3	-	ns	13
44	tCPT	/CAS Precharge Time (CBR Counter Test)	20	-	25	-	25	-	ns	
45	tROH	/RAS Hold Time Reference to /OE	15	-	15	-	15	-	ns	13
46	tOEA	/OE Access Time	-	20	-	23	-	25	ns	13
47	tOED	/OE to Data Delay Time	20	-	23	-	25	-	ns	13
48	tOEZ	Output Buffer Turn Off Delay Time from /OE	5	20	5	23	5	25	ns	8,13
49	tOEH	/OE Command Hold Time	15	-	18	-	20	-	ns	
50	tCPWD	/WE Delay Time from /CAS Precharge	54	-	62	-	69	-	ns	11
51	tRHCP	/RAS Hold Time from /CAS Precharge	37	-	42	-	47	-	ns	13
52	tWRP	/WE to /RAS Precharge Time(CBR cycle)	12	-	12	-	12	-	ns	13
53	tWRH	/WE to /RAS Hold Time (CBR cycle)	8	-	8	-	8	-	ns	13
54	tRASS	/RAS Pulse Width (Self Refresh)	100	-	100	-	100	-	μs	
55	tRPS	/RAS Precharge Time (Self Refresh)	110	-	130	-	150	-	ns	
56	tCHS	/CAS Hold Time (Self Refresh)	-50	-	-50	-	-50	-	ns	
57	tDOH	Output Data Hold Time	10	-	10	-	10	-	ns	13
58	tREZ	Output Buffer Turn Off Delay from /RAS	3	15	3	18	3	20	ns	
59	tWEZ	Output Buffer Turn Off Delay from /WE	3	20	3	23	3	25	ns	13
60	tWED	/WE to Data Delay Time	20	-	23	-	25	-	ns	13
61	tOEP	/OE Precharge Time	5	-	5	-	5	-	ns	
62	tWPE	/WE Pulse Width (EDO cycle)	5	-	5	-	5	-	ns	
63	tOCH	/OE to /CAS Hold Time	5	-	5	-	5	-	ns	
64	tCHO	/CAS Hold Time to /OE	5	-	5	-	5	-	ns	

NOTE

1. An initial pause of 200 μ s is required after power-up followed by 8 /RAS only refresh cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 CBR refresh cycles instead of 8 /RAS only refresh cycles are required.
2. $t_{ASC} \geq t_{CP}(\text{min.})$, assume $t_T=2\text{ns}$
3. $V_{IH}(\text{min.})$ and $V_{IL}(\text{max.})$ are reference levels for measuring timing of input signals. Transition times are measured between $V_{IH}(\text{min.})$ and $V_{IL}(\text{max.})$
4. The minimum specifications are used only to indicate cycle time at which proper operation over the full temperature range ($T_A = 0$ to 70°C) is assured.
5. Measured at $V_{OH}=2.0\text{V}$ and $V_{OL}=0.8\text{V}$ with a load equivalent to 1 TTL loads and 100pF.
6. Operation within the $t_{RCD}(\text{max.})$ limit insures that $t_{RAC}(\text{max.})$ can be met. $t_{RCD}(\text{max.})$ is specified as a reference point only. If t_{RCD} is greater than the specified $t_{RCD}(\text{max.})$ limit, then access time is controlled by t_{CAC}
7. Operation within the $t_{RCD}(\text{max.})$ limit insures that $t_{RAC}(\text{max.})$ can be met. $t_{RAD}(\text{max.})$ is specified as a reference point only. If t_{RAD} is greater than the specified $t_{RAD}(\text{max.})$ limit, then access time is controlled by t_{AA}
8. $t_{CEZ}(\text{max.})$, $t_{OEZ}(\text{max.})$, $t_{REZ}(\text{max.})$ and $t_{WEZ}(\text{max.})$ define the time at which the output achieves the open circuit condition and is not referred to output voltage levels.
9. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle..
10. These parameters are referred to /CAS leading edge in early write cycles and to /WE leading edge in Read-Modify-Write cycles.
11. t_{WCS} , t_{RWD} , t_{CWD} , t_{AWD} and t_{CPWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geq t_{WCS}(\text{min.})$, the cycle is an early write cycle and data out pin will remain open circuit (high impedance) through the entire cycle. If $t_{CWD} \geq t_{CWD}(\text{min.})$, $t_{RWD} \geq t_{RWD}(\text{min.})$ and $t_{CPWD} \geq t_{CPWD}(\text{min.})$, then the cycle is a Read-Modify-Write cycle and data out will contain data read from the selected cell. If neither of the above conditions is satisfied, the condition of the data out is indeterminate.
12. If /RAS goes to high before /CAS high going, the open circuit condition of the output is achieved by /CAS high going. If /CAS goes to high before /RAS high going, the open circuit condition of the output is achieved by /RAS high going.
13. The timing skew from the DRAM to the DIMM resulted from the addition of buffers.

CAPACITANCE

($T_A=25^\circ\text{C}$, $V_{CC}=3.3\text{V} \pm 0.3\text{V}$, $V_{SS}=0\text{V}$ and $f = 1\text{MHz}$, unless otherwise noted.)

SYMBOL	PARAMETER	TYP.	MAX.	UNIT
CIN1	Input Capacitance (A0~A11, B0)	-	20	pF
CIN2	Input Capacitance (/RAS0~/RAS3)	-	81	pF
CIN3	Input Capacitance (/CAS0, /CAS4, /CAS1, /CAS5, /WE0, /WE2, /OE0, /OE2)	-	20	pF
CDQ	Data Input /Output Capacitance (DQ0~DQ71)	-	24	pF

PACKAGE INFORMATION
168 pin Buffered Dual In-line Memory Module (TSOP-II Mounted)
